RF Exposure Report

Test report
On Behalf of
Dongguan Taide Intelligence Technology Co., Ltd.
For
Wireless Bluetooth Speaker

Model No.: BT295

FCC ID: 2ARIDBT295

Prepared for :	**Dongguan Taide Intelligence Technology Co.,Ltd** **Taide Technology Park, Jinfenghuang, Industrial Distrial, Fenggang Town, Dongguan City, China**
Prepared By :	**Shenzhen HUAK Testing Technology Co., Ltd.** **1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China**

Date of Test:	**Nov. 29, 2018 to Dec. 06, 2018**
Date of Report:	**Dec. 06, 2018**
Report Number:	**HK1812061813E**

TEST RESULT CERTIFICATION

Applicant's name	:	Dongguan Taide Intelligence Technology Co.,Ltd.
Address	:	Taide Technology Park, Jinfenghuang, Industrial Distrial, Fenggang Town, Dongguan City, China
Manufacture's Name	:	Dongguan Taide Intelligence Technology Co.,Ltd.
Address	:	Taide Technology Park, Jinfenghuang, Industrial Distrial, Fenggang Town, Dongguan City, China

Product description

Trade Mark:		MINISO
Product name	:	Wireless Bluetooth Speaker
Model and/or type reference	:	BT295
Standards	:	KDB 680106 D01 RF Exposure Wireless Charging Base App v03

Date of Test	:	
Date (s) of performance of tests	:	Nov. 29, 2018 to Dec. 06, 2018
Date of Issue	:	Dec. 06, 2018
Test Result	:	**Pass**

Testing Engineer : Gary Qian

(Gary Qian)

Technical Manager : Eden Hu

(Eden Hu)

Authorized Signatory : Jason Zhou

(Jason Zhou)

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1. TEST SUMMARY

1.1 TEST PROCEDURES AND RESULTS

DESCRIPTION OF TEST	RESULT
E and H field strength measurements	Compliant

1.2 TEST FACILITY

Test Firm : Shenzhen HUAK Testing Technology Co., Ltd.

Address : 1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

Designation Number: : CN1229

Test Firm Registration Number : 616276

1.3 MEASUREMENT UNCERTAINTY

Measurement Uncertainty

Conducted Emission Expanded Uncertainty	=	2.23dB, k=2
Radiated emission expanded uncertainty(9kHz-30MHz)	=	3.08dB, k=2
Radiated emission expanded uncertainty(30MHz-1000MHz)	=	4.42dB, k=2
Radiated emission expanded uncertainty(Above 1GHz)	=	4.06dB, k=2

2. GENERAL INFORMATION

2.1. PRODUCT DESCRIPTION

A major technical description of EUT is described as following

Operation Frequency	142.6kHz
Maximum field strength	53.61dBuV/m(Peak)@3m
Number of channels	1
Antenna Designation	Integrated Antenna (Met 15.203 Antenna requirement)
Hardware Version	BT-295_6908a+8871/BT295-BJX-02-0993
Software Version	BT295_AC6908_V2.6
Power Supply	DC 5V by adapter

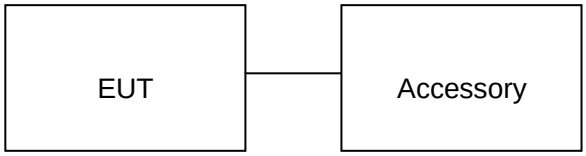
2.2 OPERATION OF EUT DURING TESTING

NO.	TEST MODE DESCRIPTION
1	Wireless charging Mode(Full load)
2	Wireless charging Mode(half load)
3	Wireless charging Mode(Null load)

Note:
1. The mode 1 was the worst case and only the data of the worst case record in this report.

2.3 DESCRIPTION OF TEST SETUP

Configure :



Item	Equipment	Model No.	ID or Specification	Remark
1	Wireless electronic Load	--	Maximum power 5W	Support
2	Adapter	RJ-AS050200E999	DC 5V/2A	AE

3. TEST EQUIPMENT LIST

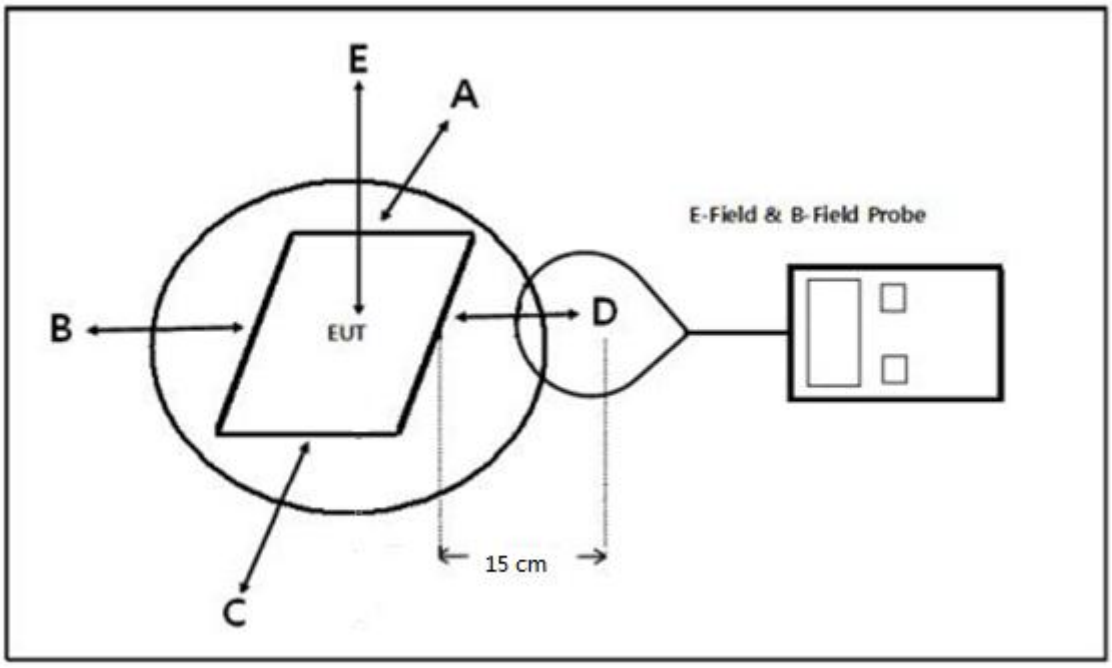
Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Broadband Field Meter	Narda Safety Test Solutions GmbH	NBM-550	J-0004	June 12, 2018	June 11, 2019
Probe FHP	Narda Safety Test Solutions GmbH	EHP-50F	J-0015	June 12, 2018	June 11, 2019

4. RADIO FREQUENCY (RF) EXPOSURE TEST

4.1. LIMITS

For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m.

4.2. TEST SETUP



Note: Position A: Front of EUT; Position B: Left of EUT; Position C: back of EUT; Position D: Right of EUT; Position E: Top of EUT(20 cm measure distance);

4.3. TEST PROCEDURE

The EUT was placed on a non-conductive table top and the ancillary equipment (e.g. mobile phone) was placed on the EUT for charging.

Maximum E-field and H-field measurements were tested 15cm from each side of the EUT. For top side the measure distance is 15cm.

Along the side of the EUT to center of E-field probe and H-field probe were positioned at the location to search maximum field strength.

4.4. TEST RESULT

Test condition: Mode 1

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
142.6kHz	0.16	0.16	0.16	0.16	2.18	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
142.6kHz	0.18	0.18	0.18	0.18	0.44	1.63

Test condition: Mode 2

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
132.5kHz	0.14	0.14	0.14	0.14	1.63	614

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
132.5kHz	0.12	0.12	0.12	0.12	0.40	1.63

Test condition: Mode 3

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limit (V/m)
124.8kHz	0.16	0.16	0.16	0.16	1.18	614

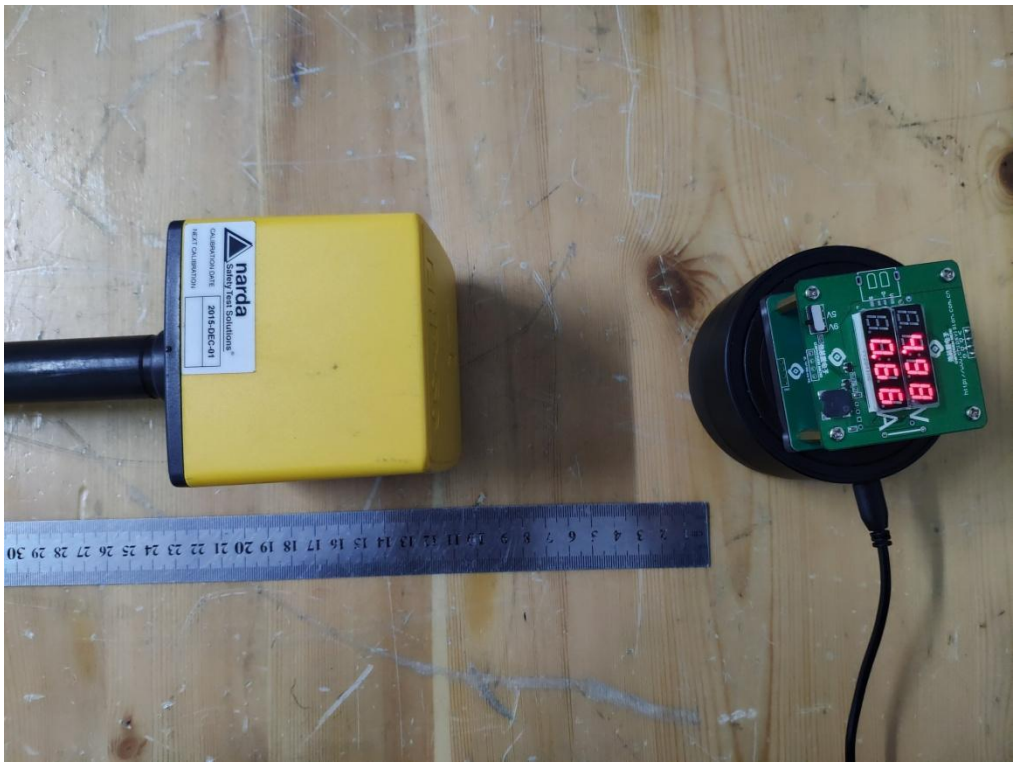
H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limit (A/m)
124.8kHz	0.13	0.13	0.13	0.13	0.34	1.63

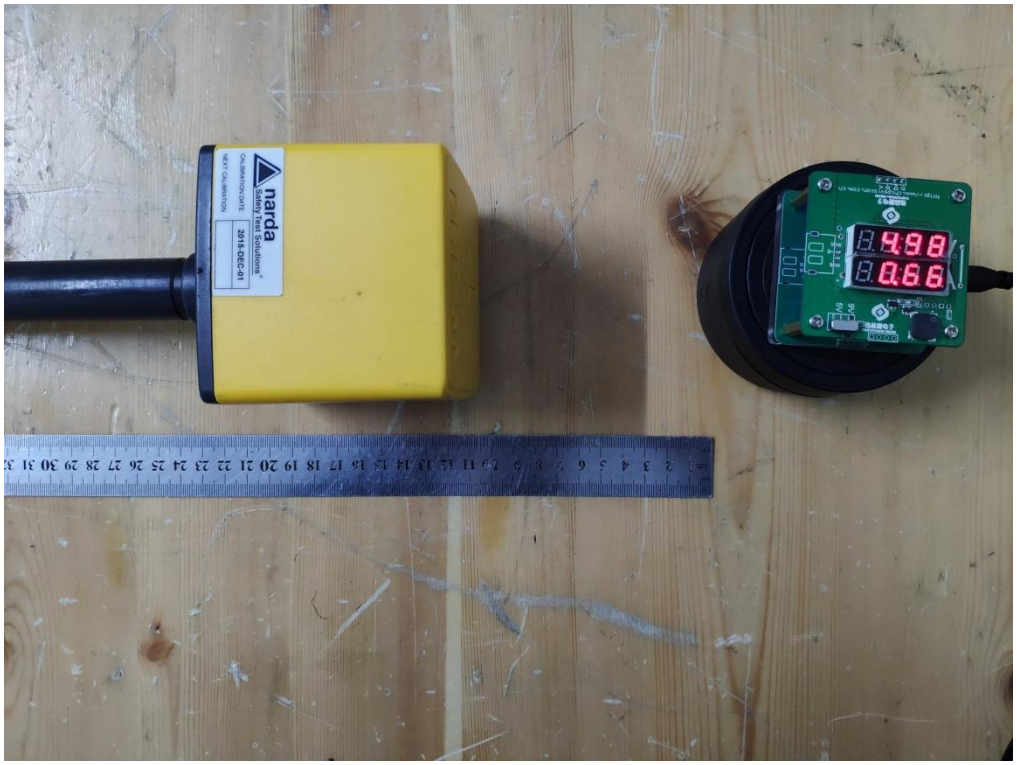
APPENDIX A: PHOTOGRAPHS OF TEST SETUP

Position E

Position A

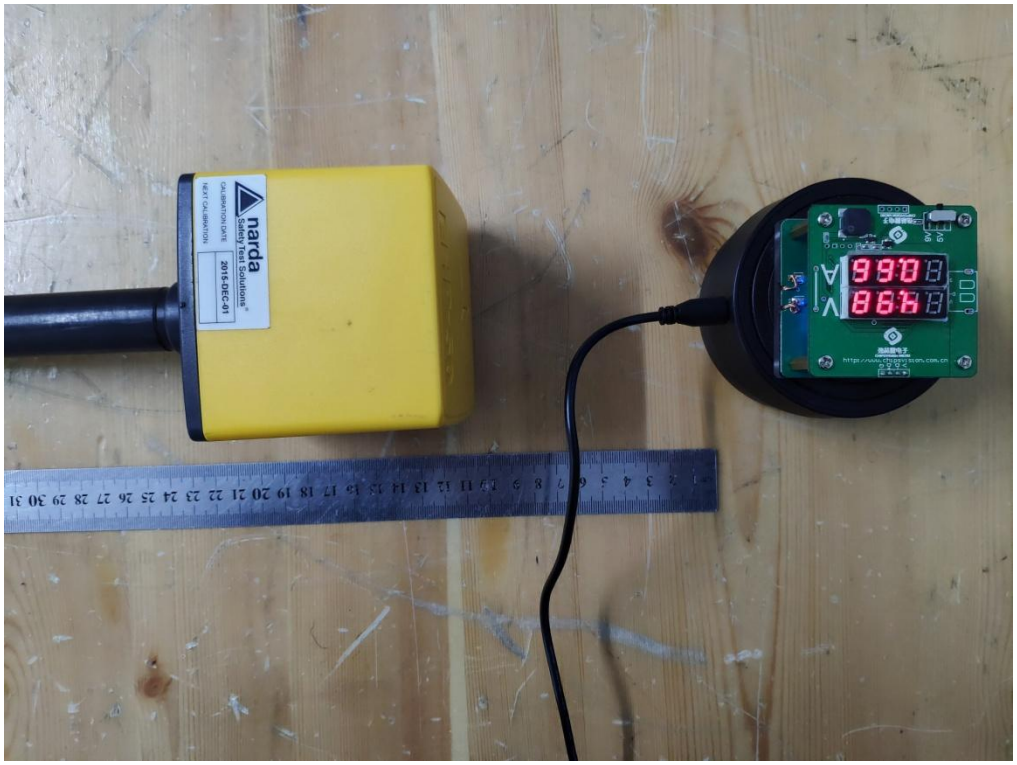


Position B



Position C

Position D



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